

## Supporting Information

### **Reversible transformation of all-inorganic copper halide perovskite nanocrystals for anti-counterfeiting**

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## **Experimental**

### **Materials**

Cesium iodide (CsI, 99.998%), copper halide (CuX, 99.999%) were obtained from Alfa. Cetyl-trimethylammonium tosylate (CTATos) was purchased from Sigma. Triethanolamine (TEAH<sub>3</sub>) and tetraethyl-orthosilicate (TEOS) were obtained from TCI. Dimethylsulfoxide (DMSO, 99.5%) was provided by Sinopharm Chemical Reagent. SBA-15 was obtained from XFNANO. Al<sub>2</sub>O<sub>3</sub> was purchased from Adamas. All chemicals were used as received without any further purification.

### **Preparation of SiO<sub>2</sub> nanospheres:**

0.96 g CTATos and 0.16 g TEAH<sub>3</sub> were dissolved in 50 mL water at 80 °C, and then TEOS was quickly injected into the solution under vigorous stirring. After 2 hours, the acquired precipitate was washed using water and ethanol for 3 times, and then annealed at 550 °C for 6 hours to remove the organic components. After grinding, white SiO<sub>2</sub> powder was obtained.

### **Preparation of Cs<sub>3</sub>Cu<sub>2</sub>I<sub>5</sub>/SiO<sub>2</sub>:**

CsI (0.3 M) and CuI (0.2 M) were dissolved in DMSO to obtain precursor solution. 50 mg SiO<sub>2</sub> powder was then mixed with 100 µL of the prepared solution, and then dried at 100 °C in vacuum to obtain Cs<sub>3</sub>Cu<sub>2</sub>I<sub>5</sub>/SiO<sub>2</sub> powder.

### **Preparation of Cs<sub>3</sub>Cu<sub>2</sub>I<sub>5</sub> nanocrystals through hot-injection method:**

Cs<sub>3</sub>Cu<sub>2</sub>I<sub>5</sub> nanocrystals were prepared following a reported procedure.<sup>1</sup> Typically, 0.1 mmol Cu(OAc)<sub>2</sub>, 0.05 mmol Cs<sub>2</sub>CO<sub>3</sub> and 1.6 mL oleic acid were mixed with 5 mL 1-octadecene in a glass vial. The vial was heated at 120 °C to completely dissolve the salts under vigorous stirring, followed by rapid injection of 0.8 mL oleylammonium iodide. After 10 s, the vial was cooled down to room temperature by using an ice water bath. Cs<sub>3</sub>Cu<sub>2</sub>I<sub>5</sub> nanocrystals were collected by centrifugation.

### **Phase transition:**

A humidifier was employed to produce continuous and fine spray. The as-obtained blue-emitting Cs<sub>3</sub>Cu<sub>2</sub>I<sub>5</sub>/SiO<sub>2</sub> was exposed to the spray treatment to realize the phase transition. When yellow-emissive CsCu<sub>2</sub>I<sub>3</sub>/SiO<sub>2</sub> was exposed to open air, it would recover to blue phase.

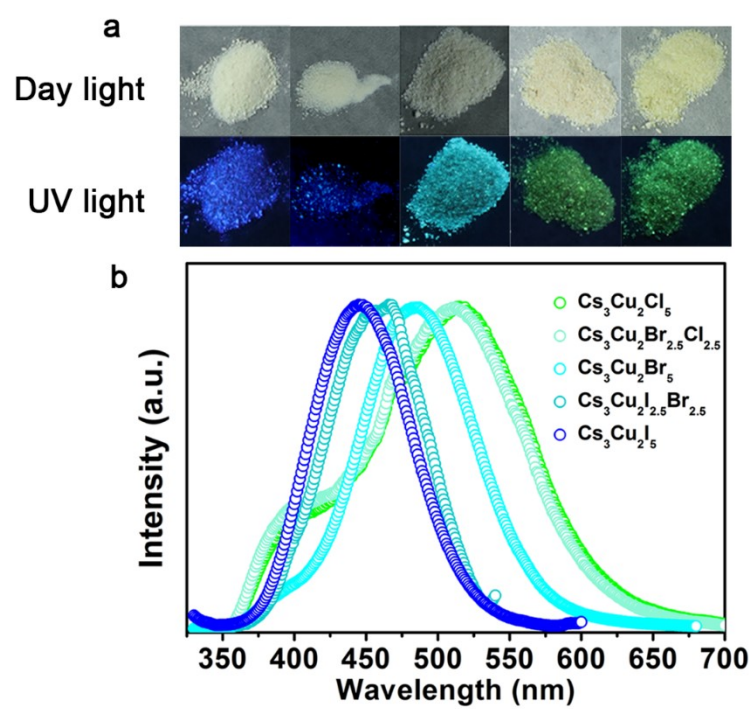
### **Scratch printing:**

Typically, a sticker was attached on the substrate such as glass and paper, and then Cs<sub>3</sub>Cu<sub>2</sub>I<sub>5</sub>/SiO<sub>2</sub> was filled in the hollow portion followed by scarping excess sample off. Next, the sticker template was removed and patterns was presented on the substrate.

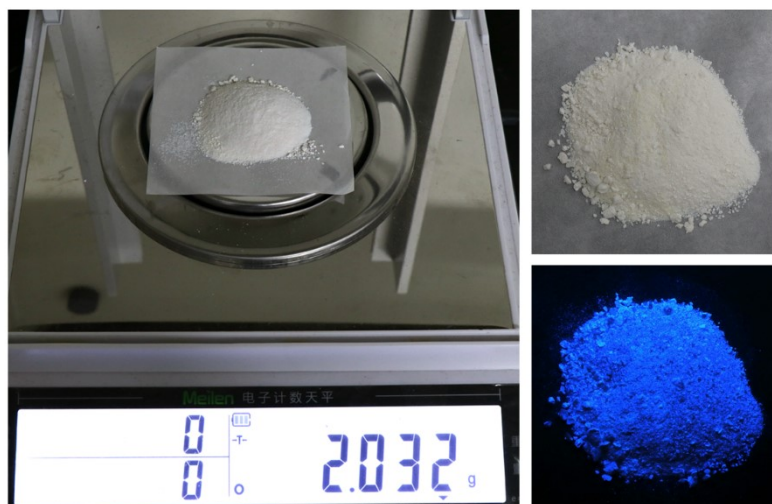
### **Characterizations:**

TEM and HRTEM images were collected on a 200 kV TECNAI G2 F20 with a Gatan SC200 CCD camera (FEI, USA). XRD were measured on a desktop diffractometer (D2 PHASER, Bruker, Germany) with a Cu K $\alpha$  source. Absorption spectra were recorded by using a UV spectrometer (SPECORD S 600, Thermo Fisher, USA). PL measurement was carried out on a fluorescence spectrophotometer

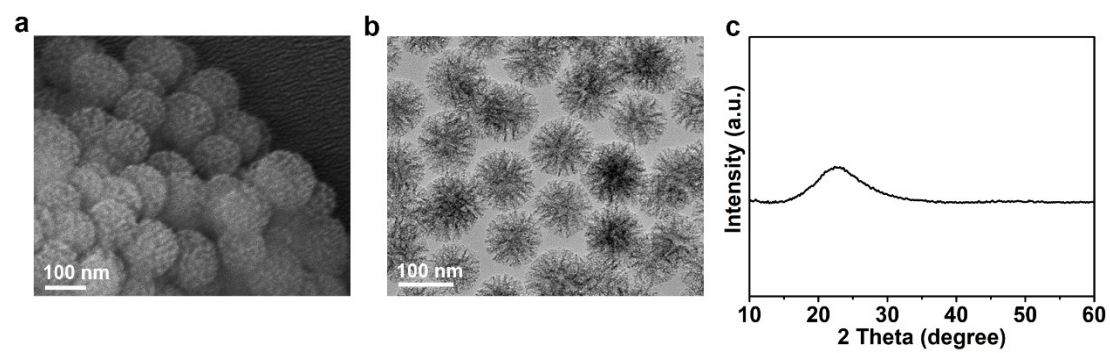
(Fluoromax-4, Hamamatsu, Japan). Zeta potential was measured using a zeta potential analyzer (ELSZ-2000, Otsuka).



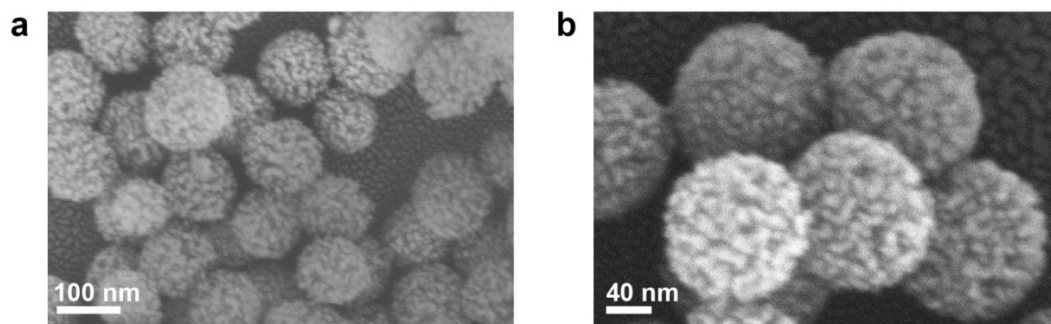
**Fig. S1** (a) Photographs and (b) PL spectra of  $\text{Cs}_3\text{Cu}_2\text{X}_5/\text{SiO}_2$  with different halide compositions.



**Fig. S2** Mass production for  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SiO}_2$ .

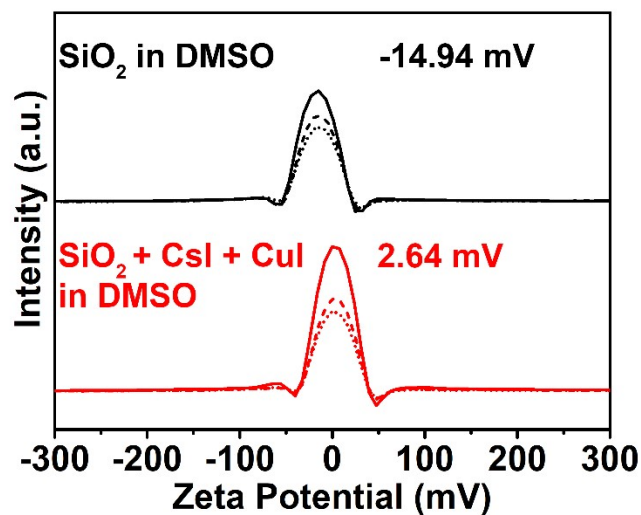


**Fig. S3** (a) SEM, (b) TEM images and (c) XRD pattern of mesoporous SiO<sub>2</sub> nanospheres.

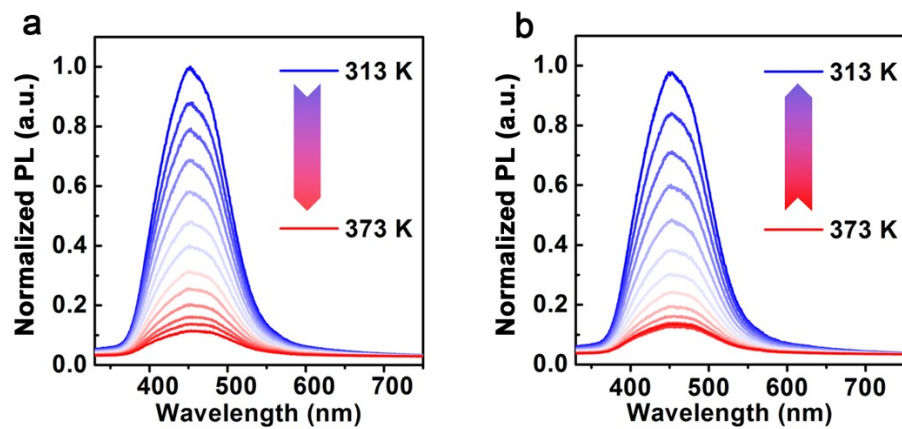


**Fig. S4** SEM images of  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SiO}_2$  composite.

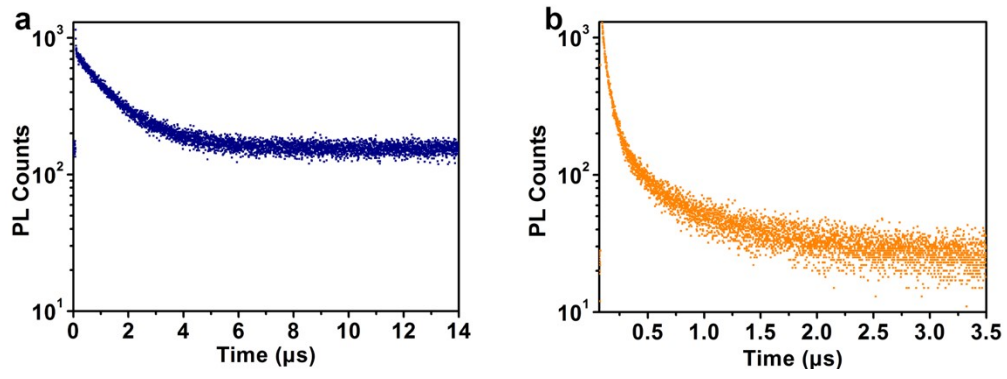




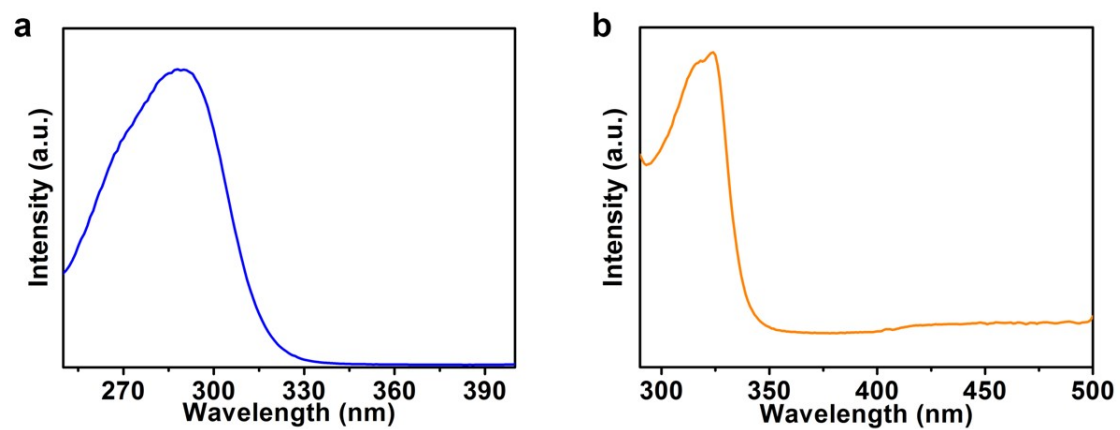
**Fig. S5** Zeta potential of SiO<sub>2</sub> dispersed in DMSO and SiO<sub>2</sub> + CsI (0.03 M)+CuI (0.02 M) in DMSO. Each samples were tested for 3 times (presented as solid, dash, dotted line, respectively) under different applied voltage to determined the average zeta potential. Their average zeta potential was -14.94 mV and 2.64 mV, respectively.



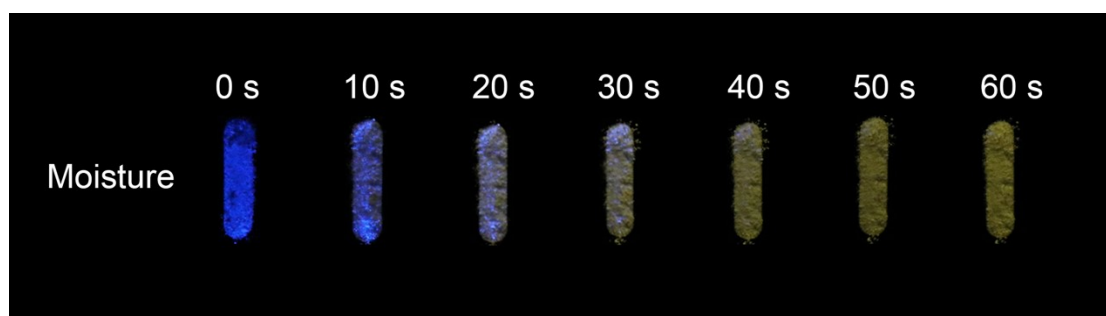
**Fig. S6** Temperature-dependent PL emission spectra of  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SiO}_2$ .



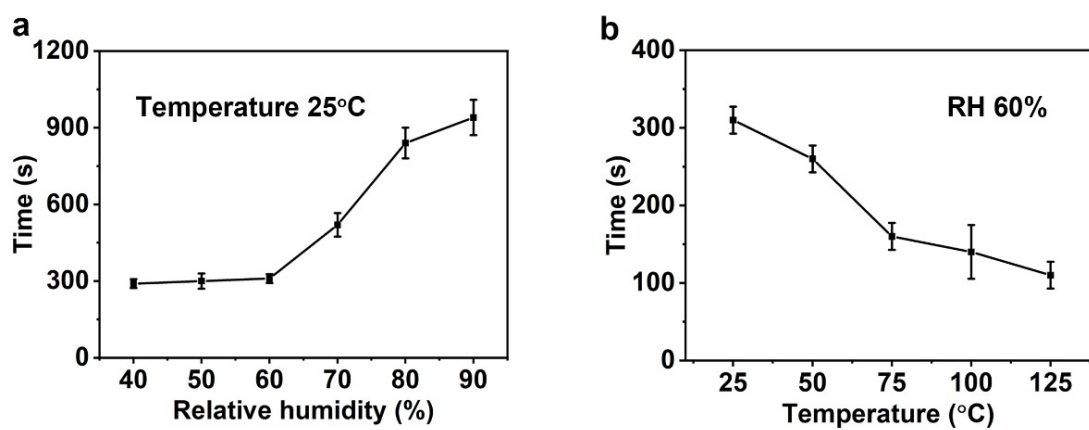
**Fig. S7** PL decays of (a)  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SiO}_2$  and (b)  $\text{CsCu}_2\text{I}_3/\text{SiO}_2$ . The average PL lifetime of  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SiO}_2$  and (b)  $\text{CsCu}_2\text{I}_3/\text{SiO}_2$  is 430 ns and 35 ns, respectively.



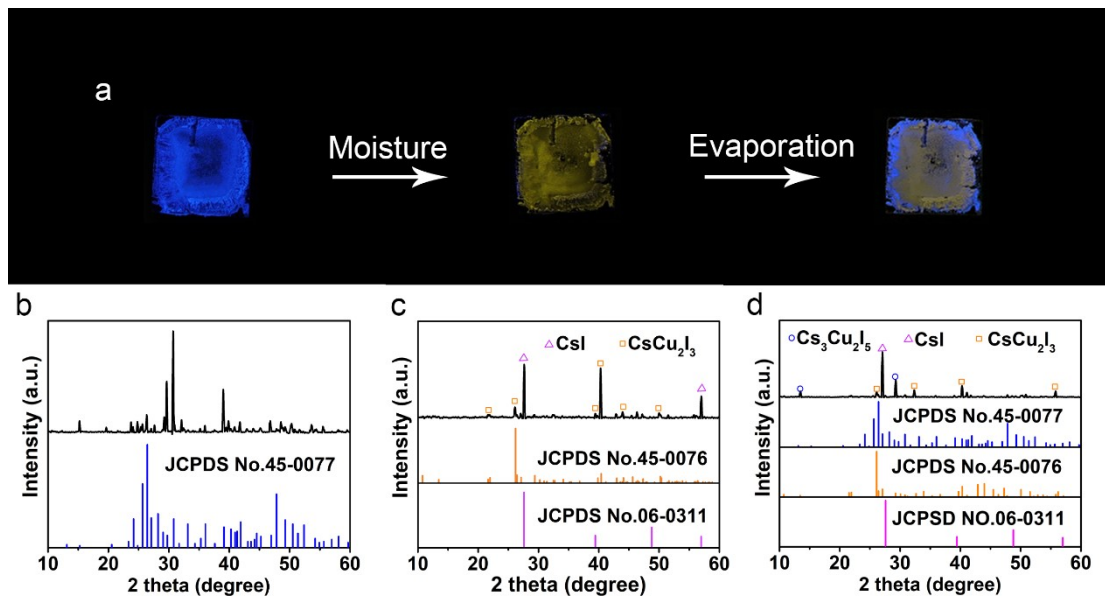
**Fig. S8** PLE spectra of (a)  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SiO}_2$  and (b)  $\text{CsCu}_2\text{I}_3/\text{SiO}_2$ .



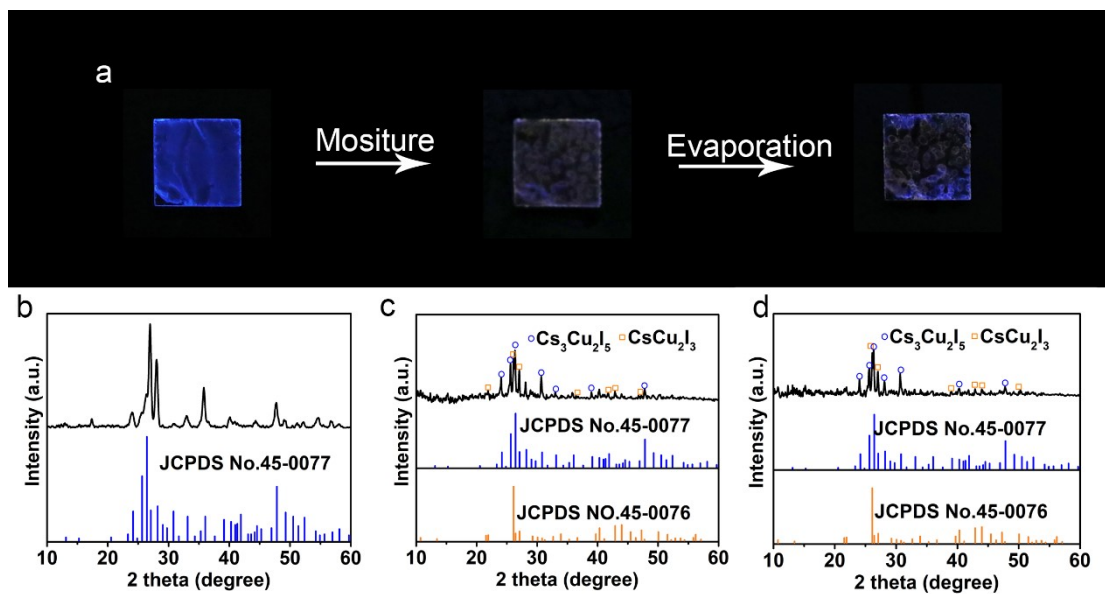
**Fig. S9** Photographs of the transformation process from  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SiO}_2$  to  $\text{CsCu}_2\text{I}_3/\text{SiO}_2$  under moisture treatment with a flow rate of  $108 \text{ mg}_{\text{water}} \text{ min}^{-1}$ .



**Fig. S10** Recovery time from  $\text{CsCu}_2\text{I}_3/\text{SiO}_2$  to  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SiO}_2$  under different (a) relative humidity and (b) temperature. In (a), temperature was constant 25 °C. In (b), relative humidity was controlled as 60%.

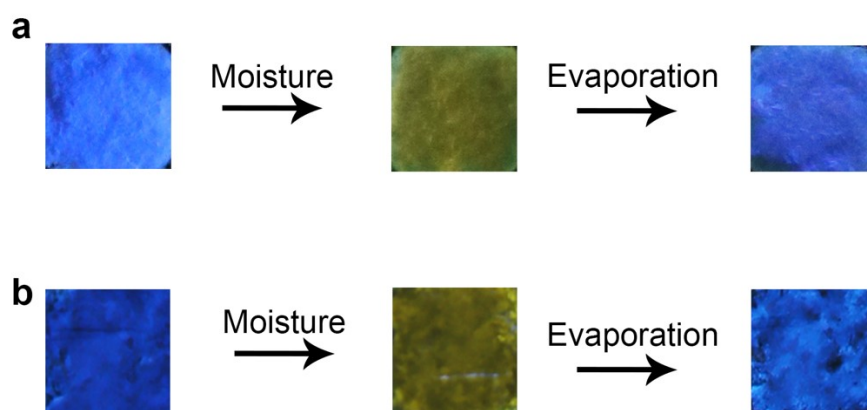


**Fig. S11** (a) Photographs of bulk  $\text{Cs}_3\text{Cu}_2\text{I}_5$  in one moisture treatment/evaporation cycle. XRD patterns of (b) initial, (c) moisture-treated and (c) recovered samples by using bulk  $\text{Cs}_3\text{Cu}_2\text{I}_5$  as the starting material.

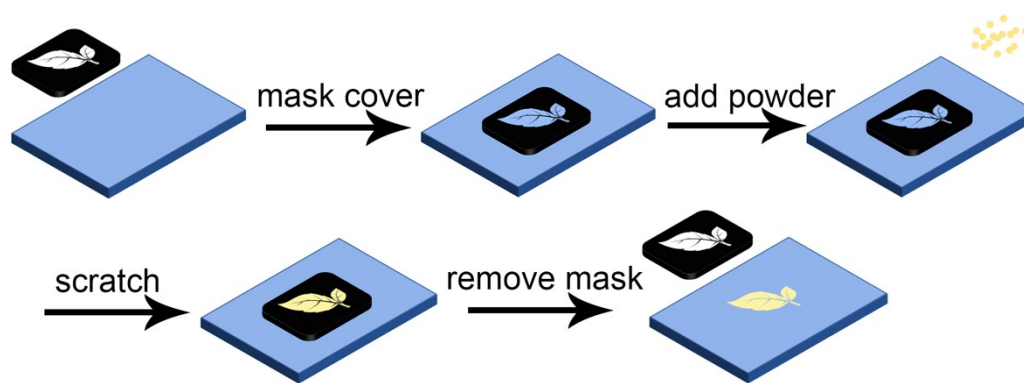


**Fig. S12** (a) Photographs of  $\text{Cs}_3\text{Cu}_2\text{I}_5$  nanocrystal film in one moisture treatment/evaporation cycle. XRD patterns of (b) initial, (c) moisture-treated and (d) recovered samples by using  $\text{Cs}_3\text{Cu}_2\text{I}_5$  nanocrystals as the starting material.





**Fig. S13** Reversible phase transitions of (a)  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{SBA-15}$  and (b)  $\text{Cs}_3\text{Cu}_2\text{I}_5/\text{Al}_2\text{O}_3$  in one moisture treatment/evaporation cycle.



**Fig. S14** Scheme illustration of scratch printing.

**Table S1** Zeta potential values measured at different voltage.

	Voltage 1	Voltage 2	Voltage 3	Average
SiO <sub>2</sub> in DMSO	-15.96	-14.49	-14.37	-14.94
SiO <sub>2</sub> +CsI+CuI in DMSO	2.98	2.60	2.32	2.64

## Reference

1. Luo, Z. S.; Li, Q.; Zhang, L. M.; Wu, X. T.; Tan, L.; Zou, C.; Liu, Y. J.; Quan, Z. W., *Small*, 2020, **16**, 1905226.